Docket No.: H0782 <u>PATENT</u>

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: David C. Newbury, et al.

: Confirmation No.:

2638

Serial No.:

10/791,130

: Art Unit:

2829

Filed:

3/1/2004

: Examiner:

Jermele M.

Hollington

For:

TEST STRUCTURE AND

METHOD FOR FAILURE ANALYSIS OF SMALL

**CONTACTS IN** 

INTEGRATED CIRCUIT

TECHNOLOGY DEVELOPMENT

Mail Stop AF Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## RESPONSE AFTER FINAL REJECTION UNDER 37 C.F.R. §1.116

Sir:

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The following Remarks are submitted under 37 C.F.R. §1.116 in response to the

Office Action mailed March 20, 2006, following the format set forth under 37 CFR §1.121.

After this introductory section there are Remarks, starting on a separate page.

Reconsideration of the rejections is respectfully requested.